

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/161,073	CHIN ET AL.
	Examiner	Art Unit
	William L. Bashore	2176

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
715	513	10/12/2006	WLB
715	536	10/12/2006	WLB
715	501.1	10/12/2006	WLB
709/217		10/12/2006	WLB